g *GE Electronic Services*	**TEST and OPERATING PROCEDURE**	
	DATE : 06/07/02	**PAGE 1 OF 3**
DISTRICT MGR:	**QUALITY REP:**	
TITLE: **193X224ACG01 PHASE CONTROLER TEST PROCEDURE**		**PROCEDURE:** **LOU-GED-193X224ACG01-B**

1. INTRODUCTORY DESCRIPTION

A. This procedure establishes the methods for testing a 193X224ACG01 Phase control card.
B. Environmental ranges: 70 +/- 10 Deg. F. with 20-75% R.H.
C. Unit warm-up/stabilization period requirement: NONE
D. Personnel using this procedure are expected to have a high degree of confidence and expertise in related testing and calibration procedures.
E. Procedures not explained here are considered to be understood as common practice.

2. TEST EQUIPMENT VERIFICATION

A. Verify the accuracy of the standard(s) used in the repair/calibration process by evidence of recent calibration labeling affixed to the test equipment.
B. All measurement standards used in this procedure shall be traceable to the NATIONAL INSTITUTE of STANDARDS and TECHNOLOGY (N.I.S.T.) and shall have the accuracy, stability, range and resolution required for the intended use.
C. Unless otherwise specified, the collective uncertainty of the Measurement Standard(s) shall not exceed twenty five percent of the acceptable tolerance for each characteristic being calibrated.
D. All deviations shall be documented.

3. EQUIPMENT CLEANING

A. All equipment clean will be performed as instructed in the GEES SOP Sec. 14.0

4. EQUIPMENT INSPECTION

A. The following criteria should be used as a guideline or basis for the inspection process of the this unit:
    1. Wires broken or cracked.
    2. Terminal strips / connectors broken or cracked.
    3. Loose wires.
    4. Components visually damaged.
    5. Capacitors leaking.
    6. Solder joint, cold.
    7. Circuit board discolored or burned.
    8. Printed wire runs burned or damaged.

5. REVISION HISTORY

Revision	Date	Initials	Reason for Revision
A	11/07/94	JDS	Initial Procedure – After Verification
B	06/07/02	RKD	Added section 5 & 6, Changed procedure number
C			
D			
E			
F			
G			
H			
I			
J			
K			

6. REFERENCE DOCUMENTATION

- Reference: GEK
- Factory Procedure #

7. THEORY OF OPERATION

A. This card in conjunction with a 193X225AAG01 control adder card is used to provide burst firing pulses to a 3 phase half-wave SCR conversion assembly.

8. TEST EQUIPMENT TO BE USED

- 193X224ACG01 Test fixture # H033530
- Oscilloscope

9. FINAL TEST AND OPERATION PROCESS

✍ It is very important to visually inspect board prior to performing tests.

- Connect BNC cable from test fixture to Vertical input on O-Scope.
- Apply power to Test Fixture and O-Scope.
- Verify that control input is 0 VDC on panel meter. If not, use the control input pot on the test fixture to adjust.
- Verify that all edge connectors of UUT are clean and insert it into the test fixture.
- Adjust the control input pot until the panel meter reads 10 VDC.
- Set the O-Scope to 5V per devision and adjust the time base until you can see all 16 pulses.

- Turn the selector switch and look at each of the 3 outputs. You should see 16 pulses on each output.
- Toggle the trigger switch and repeat last step once.
- Turn the selector switch to +20VDC and check voltage on the O-Scope.
- Adjust the control input to 0VDC and verify that there is a single pulse on each output. Adjust the control input from 0 to 10 VDC and 16 pulses should return to each output. Verify that the control input is at 10 VDC then press and hold the Suppression button. Using the selector switch, verify that a single pulse appears on each output.

10. SPECIAL INFORMATION

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TEST WRITTEN BY: David Smith **DATE:** 11/07/94

TEST VERIFIED BY: _____ **DATE:** _____